

Search Notes

Application/Control No.

10/761,297

Examiner

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Applicant(s)/Patent under
Reexamination

SUN, BEN-CHANG

Art Unit

2612

SEARCHED

Class	Subclass	Date	Examiner
341	22	12/17/2007	S.Y.
341	23, 26	12/17/2007	S.Y.
341	34	12/17/2007	S.Y.
345	172	12/17/2007	S.Y.
345	171, 173	12/17/2007	S.Y.
341	\$.ccls.	12/17/2007	S.Y.
345	\$.ccls.	12/17/2007	S.Y.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Same as	above	12/17/2007	S.Y.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched EAST: US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	12/17/2007	S.Y.
Consulted: Jeffery A. Hofssas	12/17/2007	S.Y.
Inventor Name Search: Sun-Ben-Chang.inv.	12/17/2007	S.Y.